

Data sheet acquired from Harris Semiconductor SCHS034C – Revised October 2003

CMOS Presettable Up/Down Counter

Binary or BCD-Decade
High-Voltage Types (20-Volt Rating)

■ CD4029B consists of a four-stage binary or BCD-decade up/down counter with provisions for look-ahead carry in both counting modes. The inputs consist of a single CLOCK, CARRY-IN (CLOCK ENABLE), BINARY/DECADE, UP/DOWN, PRESET ENABLE, and four individual JAM signals. Q1, Q2, Q3, Q4 and a CARRY OUT signal are provided as outputs.

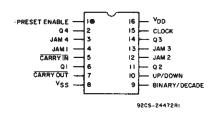
A high PRESET ENABLE signal allows information on the JAM INPUTS to preset the counter to any state asynchronously with the clock. A low on each JAM line, when the PRESET-ENABLE signal is high, resets the counter to its zero count. The counter is advanced one count at the positive transition of the clock when the CARRY-IN and PRE-SET ENABLE signals are low. Advancement is inhibited when the CARRY-IN or PRESET ENABLE signals are high. The CARRY-OUT signal is normally high and goes low when the counter reaches its maximum count in the UP mode or the minimum count in the DOWN mode provided the CARRY-IN signal is low. The CARRY-IN signal in the low state can thus be considered a CLOCK ENABLE. The CARRY-IN terminal must be connected to VSS when not in use.

Binary counting is accomplished when the BINARY/DECADE input is high; the counter counts in the decade mode when the BINARY/DECADE input is low. The counter counts up when the UP/DOWN input is high, and down when the UP/DOWN input is low. Multiple packages can be connected in either a parallel-clocking or a ripple-clocking arrangement as shown in Fig. 17.

Parallel clocking provides synchronous control and hence faster response from all counting outputs. Ripple-clocking allows for longer clock input rise and fall times.

The CD4029B-series types are supplied in 16-lead hermetic dual-in-line ceramic packages (F3A suffix), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline packages (M, M96, MT, and NSR suffixes), and 16-lead thin shrink small-outline packages (PW and PWR suffixes).

CD4029B Terminal Diagram



CD4029B Types

Features:

- Medium-speed operation . . . 8 MHz (typ.)
 © C_L = 50 pF and V_{DD}-V_{SS} = 10 V
- Multi-package parallel clocking for synchronous high speed output response or ripple clocking for slow clock input rise and fall times
- "Preset Enable" and individual "Jam" inputs provided
- Binary or decade up/down counting
- BCD outputs in decade mode
- 100% tested for quiescent current at 20 V
- 5-V, 10-V, and 15-V parametric ratings
- Standardized, symmetrical output characteristics
- Maximum input current of 1 μA at 18 V over full package-temperature range; 100 nA at 18 V and 25°C
- Noise margin (over full package-temperature range)

1 V at VDD = 5 V

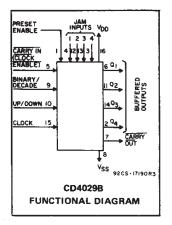
2 V at V_{DD} = 10 V

2.5 V at V_{DD} = 15 V

 Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

Applications:

- Programmable binary and decade counting/frequency synthesizers-BCD output
- Analog to digital and digital to analog conversion
- Up/Down binary counting
- Magnitude and sign generation
- Up/Down decade counting
- Difference counting



RECOMMENDED OPERATING CONDITIONS at $T_A = 25^{\circ}$ C, Except as Noted. For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	3	V _{DD}	LIN	UNITS	
		(V)	Min.	Max.	
Supply-Voltage Ran Temperature Rang	nge (For T _A = Full Package- le)		3	18	V
Setup Time t _{SU} : Càrry-In		5 10 15	200 70 60	_ _ _	
U/D or B/D		5 10 15	340 140 100	- - -	ns
Clock Pulse Width,	tw.	5 10 15	180 90 60	- - -	
Preset Enable Pulse	Width, t _W	5 10 15	130 70 50	- - -	
Clock Input Freque	ncy, fCL	5 10 15	_ _ _	2 4 5.5	MHz
Clock Rise and Fall	Time, t _r CL, t _f CL	5 10 15	- - -	15	μs

MAXIMUM RATINGS, Absolute-Maximum Values: DC SUPPLY-VOLTAGE RANGE, (VDD)	
Voltages referenced to VSS Terminal)	0.5V to +20V
INPUT VOLTAGE RANGE, ALL INPUTS	0.5V to V _{DD} +0.5V
DC INPUT CURRENT, ANY ONE INPUT	±10mA
POWER DISSIPATION PER PACKAGE (PD):	
For T _A = -55°C to +100°C	500mW
For T _A = +100°C to +125°C	
	Dorald Embarky at 12mm, O to 200mm
DEVICE DISSIPATION PER OUTPUT TRANSISTOR	
DEVICE DISSIPATION PER OUTPUT TRANSISTOR FOR TA = FULL PACKAGE-TEMPERATURE RANGE (All Package)	Types)100mW
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DEVICE DISSIPATION PER OUTPUT TRANSISTOR FOR T_A = FULL PACKAGE-TEMPERATURE RANGE (All Package OPERATING-TEMPERATURE RANGE (T_A)	Types)

STATIC ELECTRICAL	CHARACTERISTICS

CHARAC- TERISTIC	CONDITIONS											NDITIONS LIMITS A											
	v _o	VIN	V _{DD}					<u> </u>	+25		s												
	(V)	(V)	(V)	-55	-40	+85	+125	Min.	Тур.	Max.													
Quiescent		0,5	5	5	5	150	150	_	0.04	5													
Device		0,10	10	10	10	300	300	_	0.04	10	μΑ												
Current,	-	0,15	15	20	20	600	600	_	0.04	20													
UDD Wax.		0,20	20	100	100	3000	3000	_	0.08	100													
Output Low	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	-													
(Sink) Current	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	_													
I _{OL} Min.	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	-													
Output High (Source) Current,	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	_	mΑ												
	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	_													
	9.5	0,10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	_													
IOH Min.	13.5	0,15	15	-4.2	-4	-2.8	- 2.4	-3.4	-6.8	-													
Output Voltage:		0,5	5		0.	.05		0	0.05														
Low-Level,	-	0,10	10		0	.05		0	0.05														
VOL Max.	_	0,15	15		0.	-	0	0.05	V														
Output		0,5	5		4.	4.95	5	_															
Voltage: High-Level,	_	0,10	10		9.	95		9.95	10	-													
VOH Min.	_	0,15	15		14.	.95		14.95	15	_													
Input Low	0.5,4.5	-	5			1.5		_		1.5													
Voltage	1,9		10			3		-		3													
V _{IL} Max.	1.5,13.5	_	15			4		_	_	4	v												
Input High	0.5,4.5		5		3	3.5		3.5	_	_													
Voltage,	1,9	_	10	7 7 –					_	_	1												
V _{IH} Min.	1.5,13.5	1	15			11		11	_														
Input Current I _{IN} Max.	_	0,18	18	±0.1	±0.1	±1	±1	_	±10 ⁻⁵	±0.1	μА												

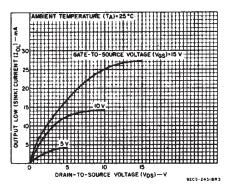


Fig. 1 — Typical output low (sink) current characteristics.

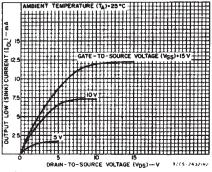


Fig. 2 — Minimum output low (sink) current characteristics.

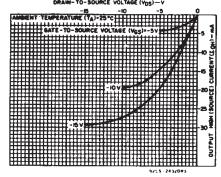


Fig. 3 - Typical output high (source) current characteristics.

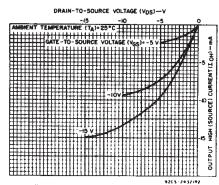


Fig. 4 — Minimum output high (source) current characteristics.

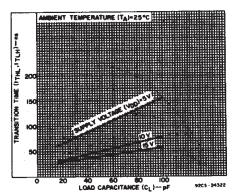


Fig. 5 — Typical transition time as a function of load capacitance.

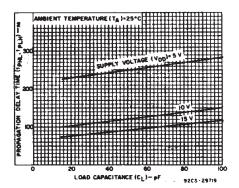


Fig. 6 — Typical propagation delay times as a function of load capacitance (Q output).

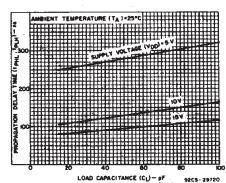


Fig. 7 — Typical propagation delay time as a function of load capacitance (carry output).

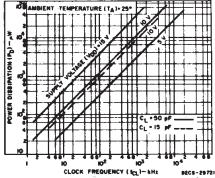
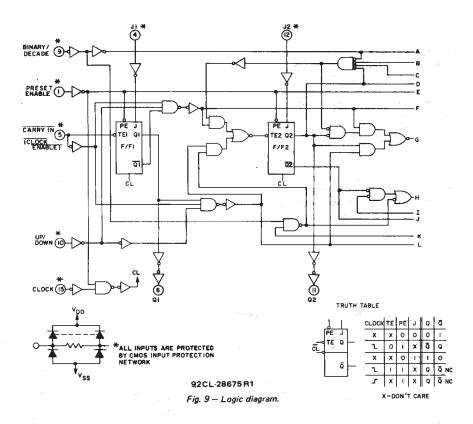


Fig. 8 – Typical power dissipation as a function of frequency.



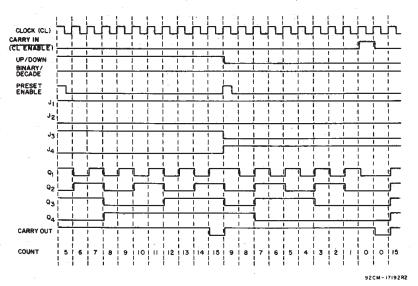


Fig. 10 - Timing diagram-binary mode.

I CD40II QUAD 2 INPUT NAND GATE

92CS-1719\$R2

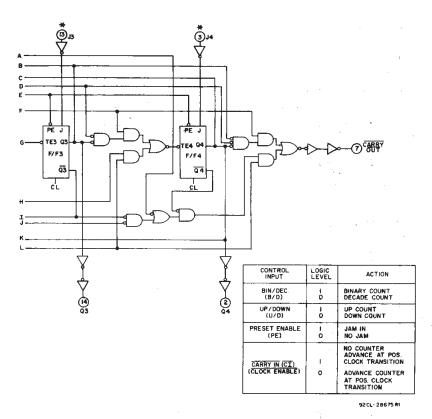
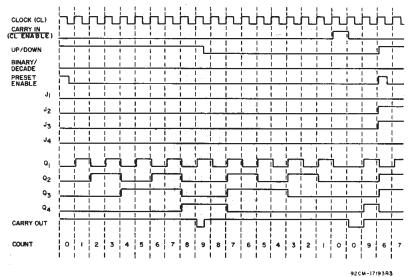


Fig. 9 - Logic diagram (cont'd).

Fig. 11 — Conversion of clock up, clock down input signals to clock and up/down input signals.

The CD4029B CLOCK and UP/DOWN inputs are used directly in most applications. In applications where CLOCK UP and CLOCK DOWN inputs are provided, conversion to the CD4029B CLOCK and UP/DOWN inputs can easily be realized by use of the circuit in Fig. 11.

CD4029B changes count on positive transitions of CLOCK UP or CLOCK DOWN inputs. For the gate configuration shown below, when counting up the CLOCK DOWN input must be maintained high and conversely when counting down the CLOCK UP input must be maintained high.



CD4029B Types

Fig. 12 - Timing diagram-decade mode.

DYNAMIC ELECTRICAL CHARACTERISTICS at T_A = 25°C, input t_f, t_f = 20 ns, C_ = 50 pF, R_ = 200 k Ω

CHARACTERISTIC	TEST CO	NDITIONS	ı	UNITS				
		V _{DD} (V)	Min.	Тур.	Max.			
Clocked Operation	.,							
Propagation Delay Time: tpHL, tpLH		5	_	250	500			
Q Output		10	_	120	240			
		15	_	90	180			
		5	_	280	560			
Carry Output		10	-	130	260			
		15	_	95	190	ns		
		5	-	100	200			
Transition Time: t _{THL} , t _{TLH}		10	-	50	100			
Q Outputs, Carry Output		15	_	40	80			
		5	-	90	180			
Minimum Clock Pulse Width, tw		10	_	45	90			
		15	-	30	60			
		5	_	_	15			
Clock Rise & Fall Time, t _F CL, t _f CL**		10	_	-	15	μs		
· '		15		_	15	'		
*		5	_	170	340			
Minimum Setup Times, ts		10	_	70	140	ns		
8/D or U/D		15	_	50	100			
		5	2	4	_			
Maximum Clock Input Frequency, fCL		10	4	8	_	MHz		
		15	5.5	11	- 1			
Input Capacitance, C _{IN}	Any Input	t	-	5	7.5	ρF		
Preset Enable								
		5		235	470			
Propagation Delay Time: tpHL, tpLH	<u> </u>	10	_	100	200			
Q Outputs	İ	15	_	80	160			
		5		320	640			
Carry Output	İ	10		145	290			
	1	15		105	210			
	1	5		65	130	ns		
Minimum Preset Enable Pulse Width, tw	ŀ	10		35	70			
"	<u> </u>	15	-	25	50			
Marine D	Ì	5	_	100	200			
Minimum Preset Enable Removal Time, tron *	1	10	_	55	110			
rime, ^t rem*	1	15	-	40	80			
Carry Input								
Propagation Delay Time: tpHL, tpLH		5	_	170	340			
Carry Output		10	_	70	140	ns		
· · ·		15		50	100			
Min. HOLD Time	Ī	5	-	25	50	ns		
tµ*** Carry In	1	10		15	30			
	1	15	_	12	25	•		
Min Set-Up Time		5	_	100	200	ns		
t _s *** Carry in	İ	10	_	35	70			
a	ł	15		30	60			

^{*} From Up/Down, Binary/Decode, Carry In, or Preset Enable Control Inputs to Clock Edge.

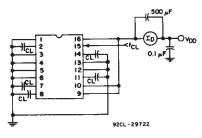


Fig. 13 - Power dissipation test circuit.

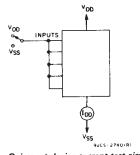


Fig. 14 - Quiescent-device current test circuit.

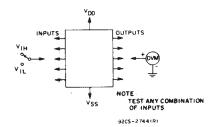


Fig. 15 - Input voltage test circuit.

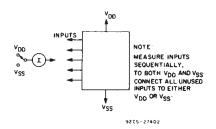
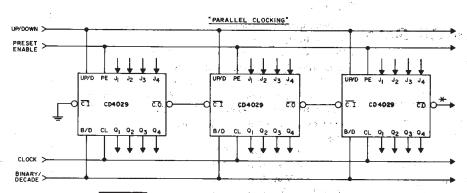


Fig. 16 - Input current test circuit.

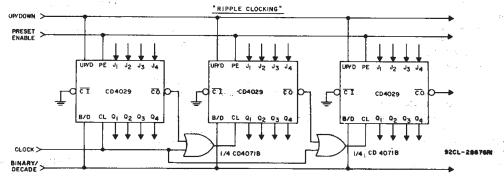
^{****}From Up/Lown, Binary/Jecode, Carry In, or Preset Enable Control injuris to Glock Edge.

***If more than one unit is cascaded in the parallel clocked application, t_vCL should be made less than or equal to the sum of the fixed propagation delay at 15 pF and the transition time of the carry output driving stage for the estimated capacitive load. This measurement was made with a decoupling capacitor (>1 µF) between V_{DD} and V_{SS}.

***From Carry In to Clock Edge



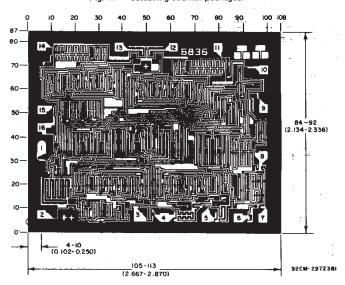
* CARRY OUT lines at the 2nd, 3rd, etc., stages may have a negative-going glitch pulse resulting from differential delays of different CD40298 fC's. These negative-going glitches do not affect proper CD40298 operation. However, if the CARRY OUT signals are used to trigger other edge-sensitive logic devices, such as FF's or counters, the CARRY OUT signals should be gated with the clock signal using a 2-input OR gate such as CD40718.



Ripple Clocking Mode:

The Up/Down control can be changed at any count. The only restriction on changing the Up/Down control is that the clock input to the first counting stage must be high. For cascading counters operating in a fixed up-count or down-count mode, the OR gates are not required between stages, and \overline{CO} is connected directly to the CL input of the next stage with \overline{CI} grounded.

Fig. 17 - Cascading counter packages.



Chip dimensions and pad layout for CD4029B

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).





6-Feb-2020

PACKAGING INFORMATION

Orderable Device	Status	Package Type	_	Pins		Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
8101602EA	ACTIVE	CDIP	J	16	1	TBD	Call TI	N / A for Pkg Type	-55 to 125	8101602EA CD4029BF3A	Samples
CD4029BE	ACTIVE	PDIP	N	16	25	Green (RoHS & no Sb/Br)	NIPDAU	N / A for Pkg Type	-55 to 125	CD4029BE	Samples
CD4029BF	ACTIVE	CDIP	J	16	1	TBD	Call TI	N / A for Pkg Type	-55 to 125	CD4029BF	Samples
CD4029BF3A	ACTIVE	CDIP	J	16	1	TBD	Call TI	N / A for Pkg Type	-55 to 125	8101602EA CD4029BF3A	Samples
CD4029BM	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4029BM	Samples
CD4029BM96	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4029BM	Samples
CD4029BNSR	ACTIVE	so	NS	16	2000	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4029B	Samples
CD4029BPWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM029B	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.



PACKAGE OPTION ADDENDUM

6-Feb-2020

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF CD4029B, CD4029B-MIL:

Catalog: CD4029B

Military: CD4029B-MIL

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

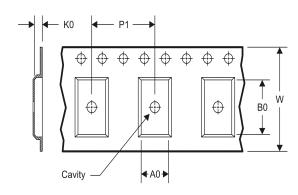
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TAPE AND REEL INFORMATION

REEL DIMENSIONS







A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

TAPE AND REEL INFORMATION

*All dimensions are nominal

All difficultions are norminal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD4029BM96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD4029BNSR	SO	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
CD4029BPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

PACKAGE MATERIALS INFORMATION

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*All dimensions are nominal

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Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD4029BM96	SOIC	D	16	2500	333.2	345.9	28.6
CD4029BNSR	SO	NS	16	2000	367.0	367.0	38.0
CD4029BPWR	TSSOP	PW	16	2000	367.0	367.0	35.0

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.





SMALL OUTLINE PACKAGE



- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



MECHANICAL DATA

NS (R-PDSO-G**)

14-PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

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